Sear	ch No	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/809,053	ICHIKAWA ET AL.
Examiner	Art Unit
Richard Hanig	2873

SEARCHED			
Class	Subclass	Date	Examiner
359	321, 322	8/18/2005	RH
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	ce Search ee printout	8/18/2005	RH

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - see printout	8/18/2005	RH
359/323; 385/2, 8; 372/102, 12 (text only - see printout)	8/18/2005	RH
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